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PERFORMANCE CHECKSHEET

Model: AVR-EB4-B
Type: Semiconductor Device Tester
S.N.: 11758
Date: June 26, 2007

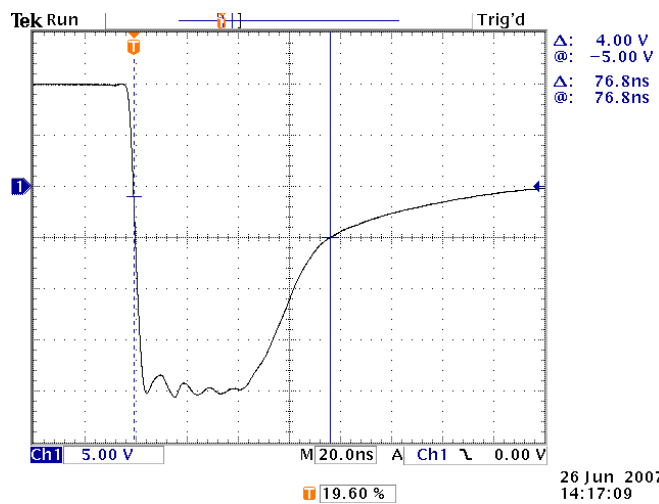
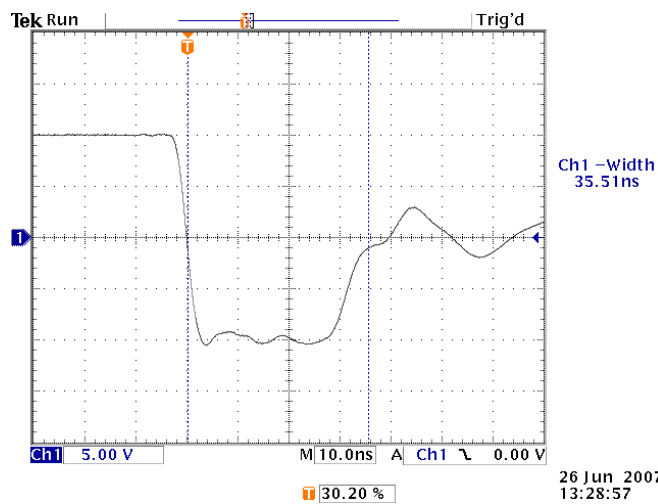
Output Amplitude: to +2A, -4A
Pulse Width (FWHM): 2 – 20 us
Switching Time,
+ to -, 20%-80%: ≤ 3 ns
PRF: 1 - 100 Hz
Jitter, Stability: OK
Prime Power: 100-240V AC, 50-60 Hz.

Basic specifications: →

Test Waveforms

With a Microsemi MQ1N5811US installed in the AVX-TRR-MSB-MELF test jig:

With On Semi 1N4937 installed in the AVX-TRRA test jig:



$I_F = +1A, I_R = -1A, I_{RR} = -0.1A.$

$I_F = +2A, I_R = -4A, I_{RR} = -1A.$

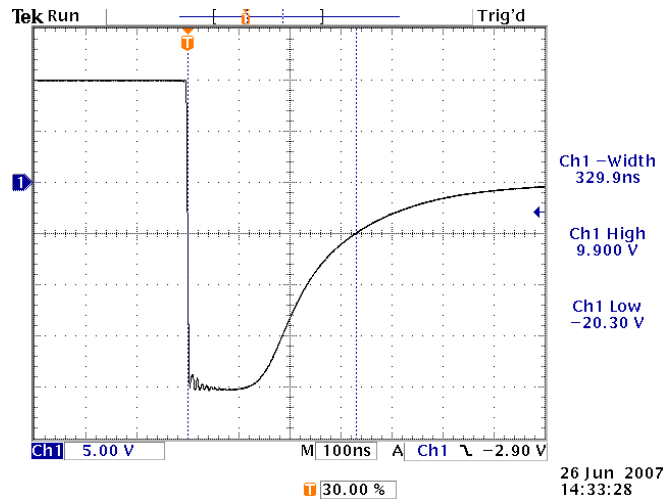
100 Hz, 20 us PW.

100 Hz, 20 us PW.

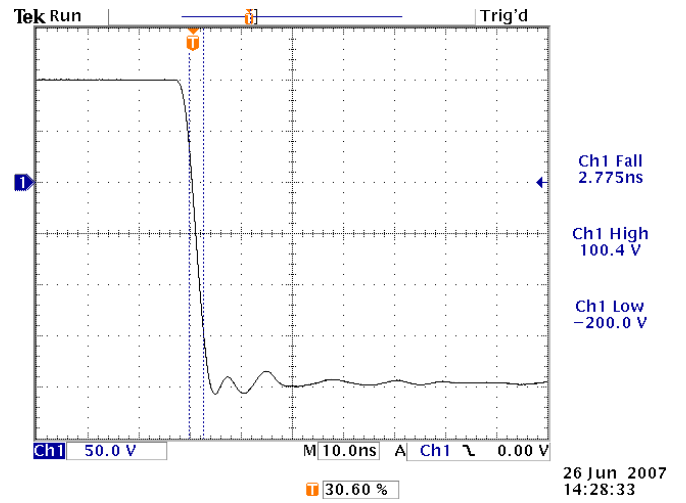
5V (1A) / div, 10 ns/div.

5V (1A) / div, 20 ns/div.

With a Ruttonsha 12FLR60/F05 installed in the AVX-TRR-MSB-STUD test jig:



Mainframe output, with AVX-TRRA test jig (and a short circuit for the DUT) installed:



$I_F = +2A$, $I_R = -4A$, $I_{RR} = -1A$.

100 Hz, 20 us PW.

5V (1A) / div, 100 ns/div.

50 V / div, 10 ns/div.